

**Search Notes**

Application/Control No.

10/066,049

Examiner

Djenane M. Bayard

Applicant(s)/Patent under  
Reexamination

PICKEL ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
709	105	7/20/2005	DB
709	225	7/20/2005	DB
709	226	7/20/2005	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	7/20/2005	DB